

# Nanoelectronics

Begriffe: to scatter - streuen CVD: chemical vapour deposition CNT: carbon nanotube DoS: Density of States

# 1 Moores Law – scaling

## 1. Transistormaterial: Germanium

Transistor scaling 22nm between drain and source of a MOSFET scaling cant continue indefinitely Against Moores Law: the rising costs of fabrication, the limits of lithography, and the size of the transistor. Advantages of scaling: smaller, cheaper, and faster and to consume less power.

# 2 Quantenmechanik

Klassische Bewegungsgleichung:  $m \frac{d^2 \mathbf{r}(t)}{dt^2} = \mathbf{F}$ Classical wave equation:

$$\frac{1}{c^2} \frac{\partial^2 \Psi}{\partial t^2} - \sum_{i=1}^n \frac{\partial^2 \Psi}{\partial x_i^2} = 0$$

$$c = \lambda f$$
$$\omega = 2\pi f$$

$$k = \frac{2\pi}{\lambda}$$
 V

behave as particles. Electrons and photons are both, particles and waves. Electron Orbits:  $mvr = n\hbar$   $n\lambda = 2\pi r$ 

De Broglie Wavelength:  $h=p\lambda$   $p=\hbar k$   $h=2\pi\hbar$ 

Uncertainty principle: 
$$\Delta x \cdot \Delta p_x \geq \frac{\hbar}{2}$$

$$\Delta E \cdot \Delta t \geq \frac{\hbar}{2}$$

# 2.1 Schroedinger Equation

$$\left(\frac{-\hbar^2}{2m}\nabla^2 + V(\underline{\boldsymbol{r}},t)\right)\Psi(\underline{\boldsymbol{r}},t) = \mathrm{j}\hbar\frac{\partial}{\partial t}\Psi(\underline{\boldsymbol{r}},t)$$

Potential energy 
$$V(\underline{r},t) \in \mathbb{R}$$
 Hamiltonian  $\hat{H} = \left( \frac{-\hbar^2}{2m} \nabla^2 + V(\underline{r},t) \right)$ 

Probabilitydensity  $\stackrel{\cdot}{P(\underline{r},t)}=\Psi(\underline{r},t)\cdot\stackrel{\cdot}{\Psi^{*}}(r,t)=|\Psi^{2}|$ Normalized:  $\int |\Psi(\underline{r})|^2 dr = 1$ 

# 2.1.1 time-independent Schroedinger equation

if  $V(\mathbf{r}, t)$  is time-independent:

$$\Psi(\underline{\boldsymbol{r}},t) = \Psi(\underline{\boldsymbol{r}}) \exp\left(\frac{\mathrm{j} E t}{\hbar}\right) \quad \Rightarrow \quad \hat{H} \Psi(\underline{\boldsymbol{r}}) = E \Psi(\underline{\boldsymbol{r}})$$

1D Confinement (infinite Quantum Well):

$$\Psi_n(x) = \sqrt{\frac{2}{L_x}} \sin\left(\frac{\sqrt{2mE}}{\hbar}x\right)$$

$$E_n = \frac{\hbar}{2m} k_n^2 = \frac{\hbar^2 \pi^2 n^2}{2mL}$$

2D Confinement 
$$\Psi(x,y) = \sqrt{\frac{4}{L_x L_y}} \sin(k_x x) \cdot \sin(k_y y)$$

$$E_n = \frac{\hbar}{2\pi i} (k_x^2 k_y^2)$$

 $\delta$ -D Confinement wirh  $\{i=x,y,...,\delta\}$ 

$$\Psi(\underline{r}) = \sqrt{\frac{2\delta}{\prod L_i}} \prod_{i=1}^{\delta} \sin(k_i \cdot i)$$

$$E_n = \frac{\hbar}{2m} (k_x^2 k_y^2)$$

Analytical solutions are only possible for the infinite quantum well

## 2.2 Quantenphysik

$$E_{Ph} = f \cdot h = \hbar \cdot \omega = \frac{hc}{\lambda}$$

$$p = \hbar k \qquad \hbar = \frac{h}{2\pi} \qquad k = \frac{2\pi}{\lambda}$$

### 2.3 Phonons

are quasiparticles to describe modes of vibrations of elastic structures of interacting particles, there are acoustic and optical phonons.

# 3 Semiconductors

### 3.1 bandstructure

Fermienergie  $F_E$ : Höchste Energie eines Elektrons bei T=0K Isolator: große Bandlücke  $E_G > 3 \mathrm{eV}$  Halbleiter: kleine Bandlücke  $1 \mathrm{eV} < 1 \mathrm{eV}$  $E_G < 3eV$  kann durch thermische Energie überwunden werden Materials in columns:

IV: Si.Ge. III-V(GaAs, InP. GaN(BluRay), InSB).II-VI(CdSe, CsTe) IV-VI(PbS.PbSe)

Silicon in crystal structure: 5 per Cube

Chemical band structure: energylevels of diffrent atoms moving close

At finite temperature some electrons can move around,  $n \propto$  $\exp(Tb_{qap})$ 

At  $300K : n = 1.5 \times 10^{1}0cm^{3}$ 

doping with donors(P,As) or acceptors(B,In) to lower the energy for emission or capture an electron atoms:  $10^23$  per cm<sup>3</sup>, dopants:  $10^15$  per cm<sup>3</sup>

$$\begin{split} E_{kin} &= \frac{p^2}{2m} = \frac{\hbar^2 k^2}{2m} \qquad \frac{\mathrm{d}^2 E}{\mathrm{d} p^2} = \frac{1}{m} \\ \text{Effektiv mass: } \frac{1}{m_{eff}^*} &= \frac{1}{\hbar} \cdot \frac{\mathrm{d}^2 E}{\mathrm{d} k^2} \end{split}$$

Resistorequation:  $R_{Mat} = \rho_{Mat} \frac{l}{wt}$ conductivity:  $\sigma = \frac{1}{2} = q\mu_n n_i$ resistivity: o

uncrtainity for electron:  $\Delta x > \frac{0.5 \cdot 10^{-4}}{^{\Lambda}}$ 

$$\begin{split} v_{sat} \text{ for Si: } 2 \cdot 10^7 \frac{cm}{s} \\ I_{DS} &= \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{DD} - V_T)^2 \\ P &= V_{DD}^2 C_{ox} f_{max} \end{split}$$

# 4 Transistors

$$I_D = \frac{1}{2} \mu_n C'_{ox} \frac{W}{L} \cdot (V_{GS} - V_{th})^2$$
  

$$\mu_n \approx 250 \cdot 10^{-4} \frac{m^2}{V_s}, \, \mu_p \approx 100 \cdot 10^{-4} \frac{m^2}{V_s}$$

$$P_{cap} = \alpha_{01} f C_{ox} V_{DD}^{2}$$
$$f_{max} = \frac{I_{sat}}{V_{DD} C_{ox}}$$

# **4.1** scaling with factor S < 1

reduce area 
$$A = W \cdot L$$
  $A' = A \cdot S^2$  increase speed  $\tau = \frac{L}{v}$   $\tau' = \tau \cdot S$  reduce power  $P = VI\tau$   $P' = P \cdot S^3$ 

Transistorscaling in nm: 90(2003), 65(2005), 45(2007), 32(2009),

#### 4.1.1 Problem of scaling

- 1. Tunneling across the oxide
- 2. Need for new lithographic techniques
- 3. Parasitic effects due to inteconnects
- 4. Melting interconnects due to voids
- 5. High field and breakdown effects

⇒ new materials, processes and technologies needed! High-K Material (high dielectric  $\varepsilon$ ) as Gate isolator:  $\Rightarrow 1, 6 \cdot C_G$ ,  $0.01 \cdot I_{leak}$ 

Example Intels 45nm MOSFET: High-K with silicon gaten: Problems: uneven

Form: Normalgate, Dualgate, Trigate Best: Surrounding Gate: CNT - high-K - metal-gate

# 4.2 Silicon Nanowire

Fabrication: growth on a gold(Au) particle

#### 4.3 GaN - Transistors

Why GaN?

- Wide bandgaps of GaN and AlGaN (high breakdown volt.)
- high drift velocity(hf)
- strong piezoelectric effekt
- High temperature operation

HEMT-Transistor: Two substrate materials, doped and undoped ⇒ electrons move on a 2D-Sheet

Cut-Off-Frquency  $f_T = \frac{v_{Sat}}{2\pi L_a}$ :  $g_m = 1$  (no amplification anymore)

Oxide-Capacitance  $C_{ox}=\frac{\varepsilon_0\varepsilon_T}{t_{ox}}$  T-Gate: smooth electric field in the channel.

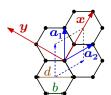
### 4.4 Quantum Wire

Ideal: just one subband in two dimensions But for good conductance(mobility, drift velocity) one need 20nm Fabrication Methods: Stressor, Etching, Ion implantation, Vicinal Growth

Split Gate Transistor: 1D tunnel in the gate between source and drain. electron wave transistor.

### 4.5 Graphene

2D Network of 3D Carbon Atoms. Stacked Layers of Graphene form Graphite. carbon nanotubes are curled graphene layers



$$b \approx 0.14\,\mathrm{nm}$$

$$d = 2b$$

$$\underline{\boldsymbol{a}}_1 = \tfrac{3}{2}b\underline{\boldsymbol{x}} + \tfrac{\sqrt{3}}{2}b\underline{\boldsymbol{y}} = \tfrac{\sqrt{3}}{2}a\underline{\boldsymbol{x}} + \tfrac{1}{2}a\underline{\boldsymbol{y}}$$

$$\underline{\boldsymbol{a}}_2 = \frac{3}{2}b\underline{\boldsymbol{x}} - \frac{\sqrt{3}}{2}b\underline{\boldsymbol{y}} = \frac{\sqrt{3}}{2}a\underline{\boldsymbol{x}} - \frac{1}{2}a\underline{\boldsymbol{y}}$$

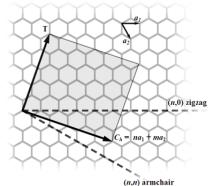
$$\|\underline{\boldsymbol{a}}_1\| = \|\underline{\boldsymbol{a}}_2\| = a = \sqrt{3}b$$
  
 $\|\underline{\boldsymbol{x}}\| = \|\boldsymbol{y}\| = 3b$ 

### 4.5.1 Properties

thinnest material sheet imagineable extremly strong (5 times stronger than steel) semimetall: better conduction than metal, can switched ON and OFF very light, good head conductor size of one cell: edge  $d \approx 0.14 nm$ . edge2edge  $a = \sqrt{3}d$ 

#### 4.6 Carbon-Nano-Tubes CNT

Propertys: diameter:  $d \approx 1$ nm Application: wires, transitors, separation membranes, sensors, capacitors Single Walled and Multiwalled: SWCNT: single layer of graphite(graphene) rolled up as cilynder



Kind of curls: zig-zag (n,0), armchair (n,n), quiral (n,m)chiral vector (tube circumfence):  $\underline{\boldsymbol{C}}_h = n\underline{\boldsymbol{a}}_1 + m\underline{\boldsymbol{a}}_2$ translation vector  $\underline{T} = [(2m + n)\underline{a}_1 - (2n + m)\underline{a}_2]/\gcd(n, m)$ Tube-Diameter:  $d_T = \frac{\|\underline{c}_h\|}{\pi} = \frac{a}{\pi} \sqrt{n^2 + nm + m^2}$  with

Kind of Nanotube:  $\begin{cases} \text{metalic} & \text{if } (n-m)/3 \in \mathbb{N}_0 \\ \text{semiconductor} & \text{else} \end{cases}$